Notice of References Cited Application/Control No. 10/618,883 Applicant(s)/Patent Under Reexamination CHEN, CHIH-WEI Examiner Art Unit Page 1 of 1

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*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	Α	US-6,643,506	11-2003	Criss et al.	455/419
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